

Notice of References Cited	Application/Control No. 10/717,502	Applicant(s)/Patent Under Reexamination MIYAKAWA ET AL.	
	Examiner Mark Eashoo, Ph.D.	Art Unit 1732	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,314,650	05-1994	Adler et al.	264/630
*	B	US-3,631,131	12-1971	Kopko	521/40.5
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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